



# MULTILEVEL PIPELINE REGISTER

IDT29FCT520AT/BT/CT

## FEATURES:

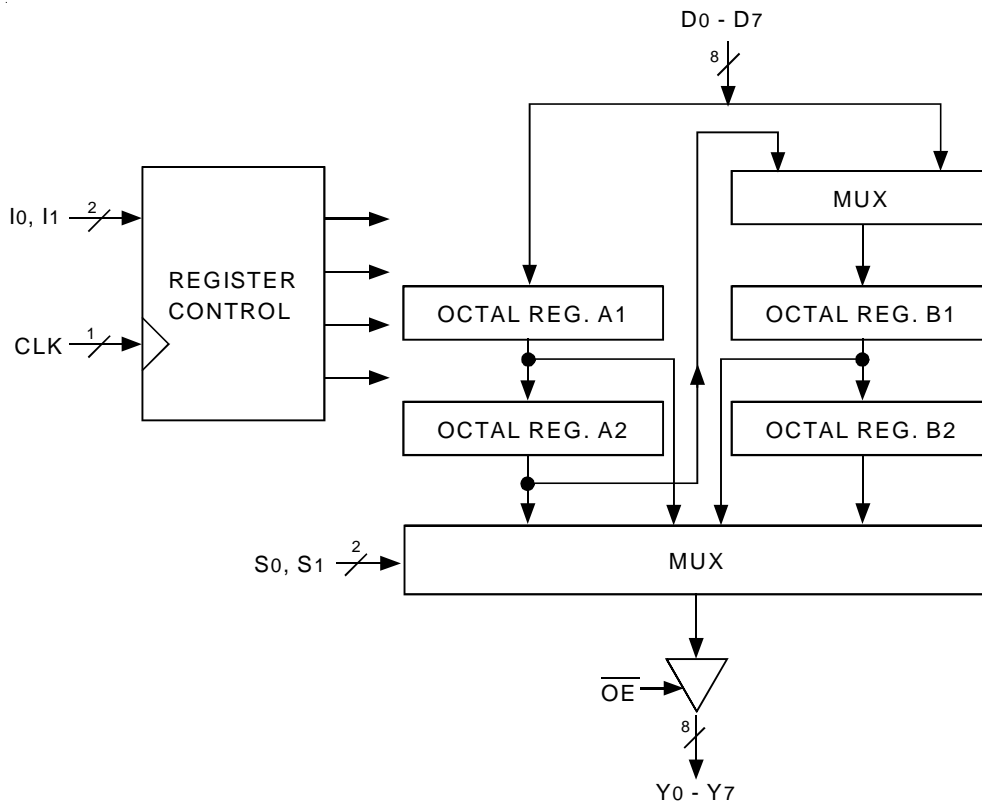
- A, B, and C grades
- Low input and output leakage  $\leq 1\mu\text{A}$  (max.)
- CMOS power levels
- True TTL input and output compatibility:
  - $V_{OH} = 3.3V$  (typ.)
  - $V_{OL} = 0.3V$  (typ.)
- High Drive outputs (-15mA  $I_{OH}$ , 48mA  $I_{OL}$ )
- Meets or exceeds JEDEC standard 18 specifications
- Available in SOIC, SSOP, and QSOP packages

## DESCRIPTION:

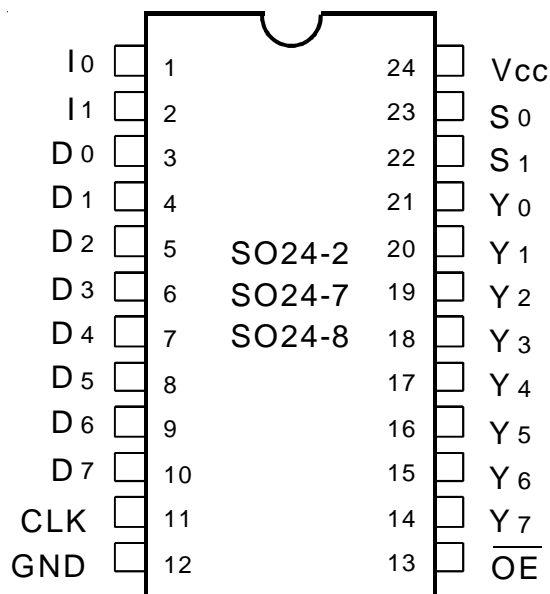
The 29FCT520T contains four 8-bit positive edge-triggered registers. These may be operated as a dual 2-level or as a single 4-level pipeline. A single 8-bit input is provided and any of the four registers is available at the 8-bit, 3-state output.

These devices are ideal for high speed burst writes and reads in processor/memory applications.

## FUNCTIONAL BLOCK DIAGRAM



## PIN CONFIGURATION



SOIC/ SSOP/ QSOP  
TOP VIEW

## ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Description	Max	Unit
VTERM <sup>(2)</sup>	Terminal Voltage with Respect to GND	-0.5 to +7	V
VTERM <sup>(3)</sup>	Terminal Voltage with Respect to GND	-0.5 to Vcc+0.5	V
TSTG	Storage Temperature	-65 to +150	°C
IOUT	DC Output Current	-60 to +120	mA

### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed Vcc by +0.5V unless otherwise noted.
- Inputs and Vcc terminals only.
- Output and I/O terminals only.

## CAPACITANCE (TA = +25°C, F = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Typ.	Max.	Unit
CIN	Input Capacitance	VIN = 0V	6	10	pF
COUT	Output Capacitance	VOUT = 0V	8	12	pF

### NOTE:

- This parameter is measured at characterization but not tested.

## PIN DESCRIPTION

Pin Names	Description
Dx	Register Input Port
CLK	Clock Input. Enter data into registers on LOW-to-HIGH transitions.
I0, I1	Instruction Inputs. See Figure 1 and INSTRUCTION CONTROL tables
S0, S1	Multiplexer Select. Inputs one of the following registers to be available at the Output Port: A1, A2, B1, or B2.
$\overline{OE}$	Output Enable for 3-State Output Port
Yx	Register Output Port

## REGISTER SELECTION

S0	S1	Register
0	0	B2
0	1	B1
1	0	A2
1	1	A1

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

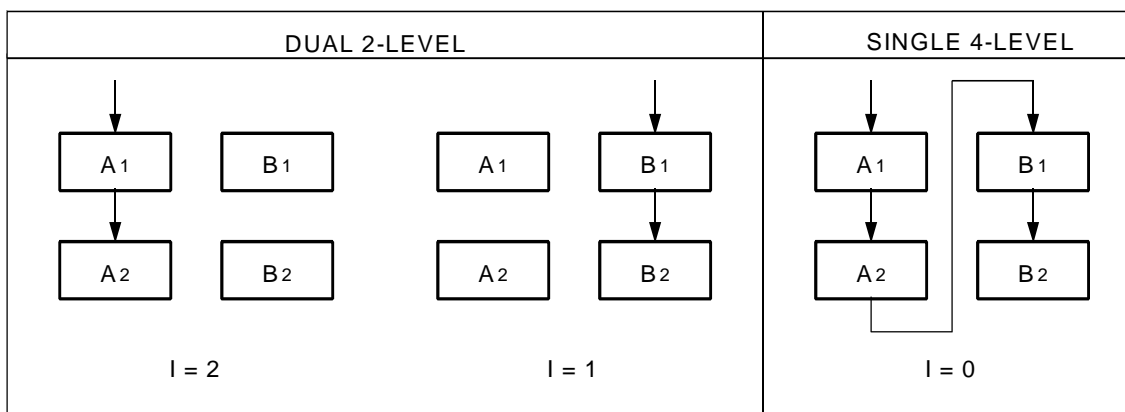
Following Conditions Apply Unless Otherwise Specified:

Industrial:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 5\%$

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
$V_{IH}$	Input HIGH Level	Guaranteed Logic HIGH Level		2	—	—	V
$V_{IL}$	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
$I_{IH}$	Input HIGH Current <sup>(4)</sup>	$V_{CC} = \text{Max.}$	$V_I = 2.7\text{V}$	—	—	$\pm 1$	$\mu\text{A}$
$I_{IL}$	Input LOW Current <sup>(4)</sup>	$V_{CC} = \text{Max.}$	$V_I = 0.5\text{V}$	—	—	$\pm 1$	$\mu\text{A}$
$I_{OZH}$	High Impedance Output Current (3-State Output pins) <sup>(4)</sup>	$V_{CC} = \text{Max.}$	$V_I = 2.7\text{V}$	—	—	$\pm 1$	$\mu\text{A}$
$I_{OZL}$			$V_I = 0.5\text{V}$	—	—	$\pm 1$	
$I_I$	Input HIGH Current <sup>(4)</sup>	$V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$		—	—	$\pm 1$	$\mu\text{A}$
$V_{IK}$	Clamp Diode Voltage	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$		—	-0.7	-1.2	V
$I_{OS}$	Short Circuit Current	$V_{CC} = \text{Max.}, V_O = \text{GND}^{(3)}$		-60	-120	-225	mA
$V_{OH}$	Output HIGH Voltage	$V_{CC} = \text{Min}$ $V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -8\text{mA}$	2.4	3.3	—	V
			$I_{OH} = -15\text{mA}$	2	3	—	
$V_{OL}$	Output LOW Voltage	$V_{CC} = \text{Min}$ $V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 48\text{mA}$	—	0.3	0.5	V
$V_H$	Input Hysteresis	—		—	200	—	mV
$I_{CC}$	Quiescent Power Supply Current	$V_{CC} = \text{Max.}, V_{IN} = \text{GND}$ or $V_{CC}$		—	0.01	1	mA

**NOTES:**

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at  $V_{CC} = 5.0\text{V}$ ,  $+25^{\circ}\text{C}$  ambient.
3. Not more than one output should be tested at one time. Duration of the test should not exceed one second.
4. The test limit for this parameter is  $\pm 5\mu\text{A}$  at  $T_A = -55^{\circ}\text{C}$ .



**NOTE:**

1.  $l = 3$  for hold.

Figure 1. Data Loading in 2-Level Operation

## POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
$\Delta I_{CC}$	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2	mA
$I_{CCD}$	Dynamic Power Supply Current <sup>(4)</sup>	$V_{CC} = \text{Max.}$ Outputs Open $\overline{OE} = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.15	0.25	mA/ MHz
$I_C$	Total Power Supply Current <sup>(6)</sup>	$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 10\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ One Bit Toggling at $f_i = 5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	1.5	3.5	mA
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	2	5.5	
		$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 10\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ Eight Bits Toggling at $f_i = 2.5\text{MHz}$ 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	3.8	7.3 <sup>(5)</sup>	
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	6	16.3 <sup>(5)</sup>	

### NOTES:

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at  $V_{CC} = 5.0V$ ,  $+25^\circ\text{C}$  ambient.

3. Per TTL driven input ( $V_{IN} = 3.4V$ ). All other inputs at  $V_{CC}$  or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.

5. Values for these conditions are examples of the  $I_{CC}$  formula. These limits are guaranteed but not tested.

6.  $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$

$I_C = I_{CC} + \Delta I_{CC} D_{HNT} + I_{CCD} (f_{CP}/2 + f_i N_i)$

$I_{CC}$  = Quiescent Current

$\Delta I_{CC}$  = Power Supply Current for a TTL High Input ( $V_{IN} = 3.4V$ )

$D_H$  = Duty Cycle for TTL Inputs High

$N_T$  = Number of TTL Inputs at  $D_H$

$I_{CCD}$  = Dynamic Current caused by an Input Transition Pair (HLH or LHL)

$f_{CP}$  = Clock Frequency for Register Devices (Zero for Non-Register Devices)

$f_i$  = Input Frequency

$N_i$  = Number of Inputs at  $f_i$

All currents are in milliamperes and all frequencies are in megahertz.

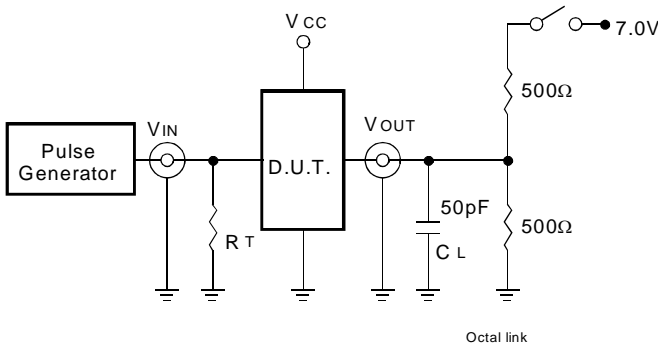
SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Symbol	Parameter	Condition <sup>(1)</sup>	29FCT520AT		29FCT520BT		29FCT520CT		Unit
			Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	
t <sub>PHL</sub> t <sub>PLH</sub>	Propagation Delay CLK to Yx	CL = 50pF RL = 500Ω	2	14	2	7.5	2	6	ns
t <sub>PHL</sub> t <sub>PLH</sub>	Propagation Delay S <sub>0</sub> or S <sub>1</sub> to Yx		2	13	2	7.5	2	6	ns
t <sub>SU</sub>	Set-up Time, HIGH or LOW Dx to CLK		5	—	2.5	—	2.5	—	ns
t <sub>H</sub>	Hold Time, HIGH or LOW Dx to CLK		2	—	2	—	2	—	ns
t <sub>SU</sub>	Set-up Time, HIGH or LOW I <sub>0</sub> or I <sub>1</sub> to CLK		5	—	4	—	4	—	ns
t <sub>H</sub>	Hold Time, HIGH or LOW I <sub>0</sub> or I <sub>1</sub> to CLK		2	—	2	—	2	—	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable Time		1.5	12	1.5	7	1.5	6	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable Time		1.5	15	1.5	7.5	1.5	6	ns
t <sub>w</sub>	Clock Pulse Width HIGH or LOW		7	—	5.5	—	5.5	—	ns

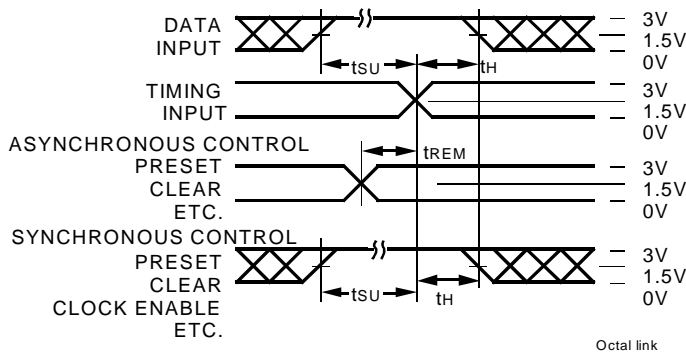
NOTES:

1. See test circuit and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.

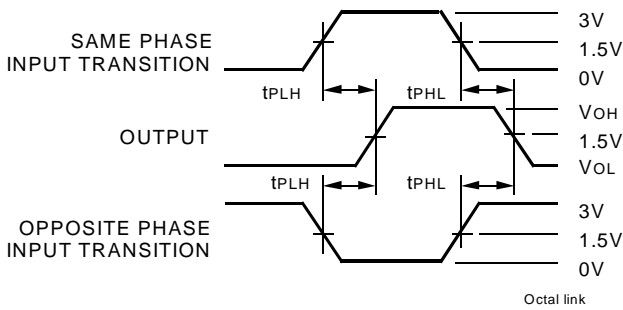
TEST CIRCUITS AND WAVEFORMS



Test Circuits for All Outputs



Set-Up, Hold, and Release Times



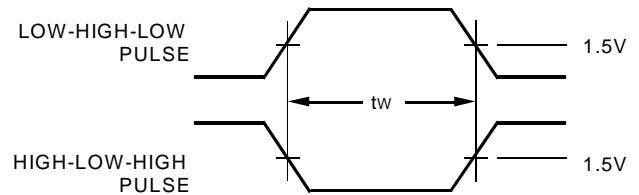
Propagation Delay

SWITCH POSITION

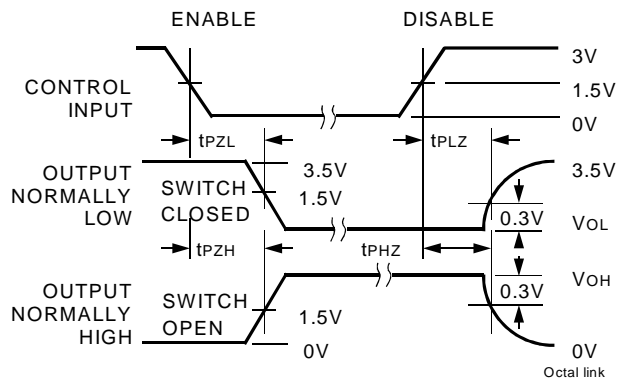
Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.  
RT = Termination resistance: should be equal to Zout of the Pulse Generator.



Pulse Width

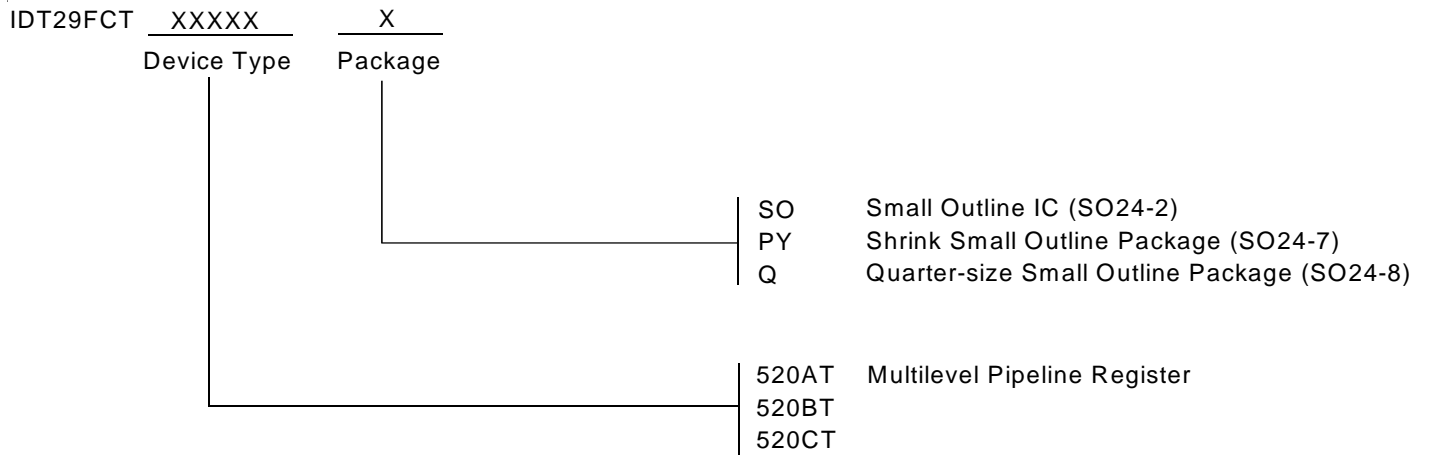


Enable and Disable Times

NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
- Pulse Generator for All Pulses: Rate ≤ 1.0MHz; tr ≤ 2.5ns; tr ≤ 2.5ns.

## ORDERING INFORMATION



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